

## EAST Search History

| Ref # | Hits    | Search Query   | DBs  | Default Operator | Plurals | Time Stamp       |
|-------|---------|--|--|------------------|---------|------------------|
| L1    | 4870561 | die\$1 or "IC"\$1 or integrated\$1circuit\$1 or (integrated adj circuit\$1) or chip\$1 or semiconductor or ic\$1chip\$1  | US-PGPUB;<br>USPAT;<br>USOCR;<br>FPRS;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2007/09/03 20:58 |
| L2    | 14274   | ((438/14) or (438/17) or (438/18) or (438/106) or (438/110) or (438/113) or (257/E21.521) or (257/E21.522) or (257/E21.524) or (257/E21.525) or (257/E21.529)).CCLS. | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB          | OR               | OFF     | 2007/09/03 20:58 |
| L3    | 4869108 | die\$1 or "IC"\$1 or integrated\$1circuit\$1 or (integrated adj circuit\$1) or chip\$1 or semiconductor or ic\$1chip\$1  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB          | OR               | ON      | 2007/09/03 20:58 |
| L4    | 12765   | L2 and L3  | US-PGPUB;<br>USPAT;<br>USOCR;<br>FPRS;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2007/09/03 20:58 |
| L5    | 3582    | (test\$3 or (failure with analysis)) with (wafer\$1level or (wafer adj level))   | US-PGPUB;<br>USPAT;<br>USOCR;<br>FPRS;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2007/09/03 20:59 |
| L6    | 393     | 4 and 5  | US-PGPUB;<br>USPAT;<br>USOCR;<br>FPRS;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2007/09/03 20:59 |